

# **Dual Channel 12-Bit 500Msps Receiver and Feedback IC**

Check for Samples: ADS54T04

#### **FEATURES**

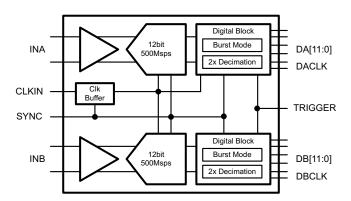
- Dual Channel
- 12-Bit Resolution
- Maximum Clock Rate: 500 Msps
- Low Swing Fullscale Input: 1.0 Vpp
- Analog Input Buffer with High Impedance Input
- Input Bandwidth (3dB): >1.2GHz
  Data Output Interface: DDR LVDS
  196-Pin BGA Package (12x12mm)
- Power Dissipation: 800mW/ch
- Performance at f<sub>in</sub> = 230 MHz IF
  - SNR: 60.6 dBFSSFDR: 77 dBc
- Performance at f<sub>in</sub> = 700 MHz IF
  - SNR: 59.4 dBFSSFDR: 70 dBc
- Receive Mode: 2x Decimation with Low Pass or High Pass Filter
- Feedback Mode: Burst Mode Output for Full Bandwidth DPD Feedback

#### **APPLICATIONS**

- Telecommunications Receiver
- Power Amplifier Linearization

#### DESCRIPTION

The ADS54T04 is a high linearity dual channel 12-bit, 500 MSPS analog-to-digital converter (ADC) easing front end filter design for wide bandwidth receivers. The analog input buffer isolates the internal switching of the on-chip track-and-hold from disturbing the signal source as well as providing a high-impedance input. Two output modes are available for the output data - it can be decimated by two or the data can be output in burst mode. The burst mode output is designed specifically for DPD feedback applications where high resolution output data is available for a short period of time. Designed for high SFDR, the ADC has low-noise performance and outstanding spurious-free dynamic range over a large inputfrequency range. The device is available in a 196pin BGA package and is specified over the full industrial temperature range (-40°C to 85°C).



Device Part No.	Number of Channels	Speed Grade
ADS54T02	2	750Msps
ADS54T01	1	750Msps
ADS54T04	2	500Msps



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### **DETAILED BLOCK DIAGRAM**

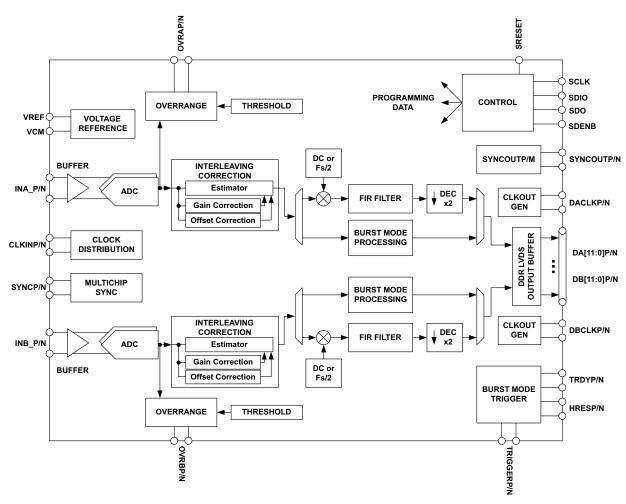


Figure 1. Detailed Block Diagram



#### **PINOUT INFORMATION**

	Α	В	С	D	E	F	G	Н	J	К	L	М	N	Р	
14	VREF	VCM	GND	INB_N	INB_P	GND	AVDDC	AVDDC	GND	INA_P	INA_N	GND	GND	CLKINP	14
13	SDENB	TEST MODE	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	CLKINN	13
12	SCLK	SRESET	GND	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	GND	AVDD33	AVDD33	12
11	SDIO	ENABLE	GND	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	GND	AVDD18	AVDD18	11
10	SDO	IOVDD	GND	AVDD18	GND	GND	GND	GND	GND	GND	AVDD18	GND	TRIGGER N	TRIGGER P	10
9	DVDD	DVDD	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	SYNCN	SYNCP	9
8	DVDD	DVDD	DVDD	DVDD	GND	GND	GND	GND	GND	GND	DVDD	DVDD	DVDD	DVDD	8
7	DB0N	DB0P	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	TRDYN	TRDYP	7
6	DB1N	DB1P	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	HRESN	HRESP	6
5	DB2N	DB2P	OVRBN	OVRBP	GND	GND	GND	GND	GND	GND	OVRAN	OVRAP	SYNC OUTN	SYNC OUTP	5
4	DB3N	DB3P	DB8P	DB10P	NC	HRESP	TRDYP	DA0P	DA2P	DA4P	DA6P	DA8P	NC	NC	4
3	DB4N	DB4P	DB8N	DB10N	NC	HRESN	TRDYN	DA0N	DA2N	DA4N	DA6N	DA8N	DA11N	DA11P	3
2	DB5N	DB5P	DB7P	DB9P	DB11P	SYNC OUTP	DBCLKP	DACLKP	DA1P	DA3P	DA5P	DA7P	DA10N	DA10P	2
1	DB6N	DB6P	DB7N	DB9N	DB11N	SYNC OUTN	DBCLKN	DACLKN	DA1N	DA3N	DA5N	DA7N	DA9N	DA9P	1
	А	В	С	D	E	F	G	Н	J	К	L	М	N	Р	•

Figure 2. Pinout in DDR output mode (top down view)

#### **PIN ASSIGNMENTS**

	BILL		T
	PIN	1/0	DESCRIPTION
NAME	NUMBER	1,0	DESCRIPTION
INPUT/REFER	ENCE		
INA_P/N	K14, L14	I	Analog ADC A differential input signal.
INB_P/N	E14, D14	I	Analog ADC B differential input signal.
VCM	B14	0	Output of the analog input common mode (nominally 1.9V). A 0.1µF capacitor to AGND is recommended.
VREF	A14	I	Reference voltage input. A 0.1µF capacitor to AGND is recommended, but not required.
CLOCK/SYNC			
CLKINP/N	P14, P13	I	Differential input clock
SYNCP/N	P9, N9	ı	Synchronization input. Inactive if logic low. When clocked in a high state initially, this is used for resetting internal clocks and digital logic and starting the SYNCOUT signal. Internal $100\Omega$ termination.
CONTROL/SE	RIAL		
SRESET	B12	I	Serial interface reset input. Active low. Initialized internal registers during high to low transition. Asynchronous. Internal $50k\Omega$ pull up resistor to IOVDD.



# **PIN ASSIGNMENTS (continued)**

PIN			
NAME	NUMBER	I/O	DESCRIPTION
ENABLE	B11	I	Chip enable – active high. Power down function can be controlled through SPI register assignment. Internal $50k\Omega$ pull up resistor to IOVDD.
SCLK	A12	ı	Serial interface clock. Internal 50kΩ pull-down resistor.
SDIO	A11	I/O	Bi-directional serial data in 3 pin mode (default). In 4-pin interface mode (register x00, D16), the SDIO pin in an input only. Internal $50k\Omega$ pull-down.
SDENB	A13	I	Serial interface enable. Internal 50kΩ pull-down resistor.
SDO	A10	0	Uni-directional serial interface data in 4 pin mode (register x00, D16). The SDO pin is tristated in 3-pin interface mode (default). Internal $50k\Omega$ pull-down resistor.
TESTMODE	B13	_	Factory internal test, do not connect
DATA INTERFA	CE		
DA[11:0]P/N	P3, N3, P2, N2, P1, N1, M4, M3, M2, M1, L4, L3, L2, L1, K4, K3, K2, K1, J4, J3, J2, J1, H4, H3	0	ADC A Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DB[11:0]P/N	E2, E1, D4, D3, D2, D1, C4, C3, C2, C1, B1, A1, B2, A2, B3, A3, B4, A4, B5, A5, B6, A6, B7, A7	0	ADC B Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DACLKP/N	H2, H1	0	DDR differential output data clock for Bus A. Register programmable to provide either rising or falling edge to center of stable data nominal timing.
DBCLKP/N	G2, G1	0	DDR differential output data clock for Bus B. Register programmable to provide either rising or falling edge to center of stable data nominal timing. Optionally Bus B can be latched with DACLKP/N.
SYNCOUTP/N	F2, F1, P5, N5	0	Synchronization output signal for synchronizing multiple ADCs. Can be disabled via SPI.
OVRAP/N	M5, L5	0	Bus A, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
OVRBP/N	D5, C5	0	Bus B, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
TRIGGERP/N	P10, N10	I	Trigger used for High resolution output data in feedback mode. Internal $100\Omega$ termination
TRDYP/N	G4, G3, P7, N7	0	Trigger ready output indicator. Outputs for chA and chB are identical and one output can be shared for both channels.
HRESP/N	F4, F3, P6, N6	0	Indicator for high resolution output data—logic high signals 12bit output data. Outputs for chA and chB are identical and one output can be shared for both channels.
NC	E3, E4, N4, P4	_	Don't connect to pin
POWER SUPPL	Y		
AVDD33	D12, E12, F12, G12, H12, J12, K12, L12, N12, P12	I	3.3V analog supply
AVDDC	G14, H14	I	1.8V supply for clock input
AVDD18	D10, D11, E11, F11, G11, H11, J11, K11, L10, L11, N11, P11	I	1.8V analog supply
DVDD	A8, A9, B8, B9, C8, D8, L8, M8, N8, P8	I	1.8V supply for digital block
DVDDLVDS	C6, C7, D6, D7, L6, L7, M6, M7	I	1.8V supply for LVDS outputs
IOVDD	B10	I	1.8V for digital I/Os
GND		I	Ground

Product Folder Links: ADS54T04

Submit Documentation Feedback

Copyright © 2012–2014, Texas Instruments Incorporated



#### **PACKAGE/ORDERING INFORMATION**

PRODUCT	PACKAGE- LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	ECO PLAN <sup>(2)</sup>	LEAD/ BALL FINISH	PACKAGE MARKING	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY
				GREEN			ADS54T04IZAY	Tray
ADS54T04	196-BGA	ZAY	-40C to 85C	(RoHS & no Sb/Br)		ADS54T04I	ADS54T04IZAYR	Tape and Reel

#### **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted)

		VA	ALUE	UNIT	
		MIN			
Supply voltage range, AVDD3	3	-0.5	4	V	
Supply voltage range, AVDDO	-0.5	2.3	V		
Supply voltage range, AVDD1	-0.5	2.3	V		
Supply voltage range, DVDD	-0.5	2.3	V		
Supply voltage range, DVDDL	-0.5	2.3	V		
Supply voltage range, IOVDD	Supply voltage range, IOVDD			V	
	INA/B_P, INA/B_N	-0.5	AVDD33 + 0.5	V	
Valtana annii ad ta innut nina	CLKINP, CLKINN	-0.5	AVDDC + 0.5	V	
Voltage applied to input pins	SYNCP, SYNCN	-0.5	AVDD33 + 0.5	V	
	SRESET, SDENB, SCLK, SDIO, SDO, ENABLE	-0.5	IOVDD + 0.5	V	
Operating free-air temperature	e range, T <sub>A</sub>	-40	85	°C	
Operating junction temperatur		150	°C		
Storage temperature range	-65	150	°C		
ESD, Human Body Model		2	kV		

#### THERMAL INFORMATION

	THERMAL METRIC <sup>(1)</sup>	ADS54T04	LINUTO
	IHERMAL METRIC**	nFBGA (196-PIN)	UNITS
$\theta_{JA}$	Junction-to-ambient thermal resistance (2)	37.6	
$\theta_{JCtop}$	Junction-to-case (top) thermal resistance (3)	6.8	
$\theta_{JB}$	Junction-to-board thermal resistance (4)	16.8	°C/W
ΨЈТ	Junction-to-top characterization parameter <sup>(5)</sup>	0.2	
ΨЈВ	Junction-to-board characterization parameter <sup>(6)</sup>	16.4	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter,  $\psi_{JT}$ , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining  $\theta_{JA}$ , using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ<sub>JB</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).



#### RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
_	Recommended operating junction temperature			105	3
ال	Maximum rated operating junction temperature <sup>(1)</sup>	125			
T <sub>A</sub>	Recommended free-air temperature	-40	25	85	°C

<sup>(1)</sup> Prolonged use at this junction temperature may increase the device failure-in-time (FIT) rate.

#### **ELECTRICAL CHARACTERISTICS**

Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{\text{MIN}} = -40^{\circ}\text{C}$  to  $T_{\text{MAX}} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ADC Clock	Frequency		40		500	MSPS
Resolution	1		12			Bits
SUPPLY						
AVDD33			3.15	3.3	3.45	V
AVDDC, A	VDD18, DVDD, DVDDLVDS		1.7	1.8	1.9	V
IOVDD			1.7	1.8	3.45	V
POWER S	UPPLY		·			
I <sub>AVDD33</sub>	3.3V Analog supply current			297	330	mA
I <sub>AVDD18</sub>	1.8V Analog supply current			84	100	mA
I <sub>AVDDC</sub>	1.8V Clock supply current			26	45	mA
$I_{DVDD}$	1.8V Digital supply current	Auto Correction Enabled		230	260	mA
$I_{DVDD}$	1.8V Digital supply current	Auto Correction Disabled		106		mA
$I_{DVDD}$	1.8V Digital supply current	Auto Correction Disabled, decimation filter enabled		135		mA
I <sub>DVDDLVDS</sub>	1.8V LVDS supply current			120	150	mA
$I_{IOVDD}$	1.8V I/O Voltage supply current			1	2	mA
P <sub>dis</sub>	Total power dissipation	Auto Correction Enabled, decimation filter disabled		1.78	2.3	W
$P_{dis}$	Total power dissipation	Auto Correction Disabled, decimation filter disabled		1.6		W
PSRR		250kHz to 500MHz	40			dB
Shut-down	power dissipation			7		mW
Shut-down	wake up time			2.5		ms
Standby po	wer dissipation			7		mW
Standby wa	ake up time			100		μs
Doop aloon	made power dissipation	Auto correction disabled		282		mW
neeh-sieeb	mode power dissipation	Auto correction enabled		370		mW
Deep-sleep	mode wakeup time			20		μs
Light alcan	mode power dissipation	Auto correction disabled		549		mW
Ligiti-sieep	mode power dissipation	Auto correction enabled		650		mW
Light-sleep mode wakeup time				2		μs



# **ELECTRICAL CHARACTERISTICS**

Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{MIN} = -40^{\circ}\text{C}$  to  $T_{MAX} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD3V = 3.3V, AVDD/DRVDD/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ANALOG INPUTS		1			
Differential input full-scale			1.0	1.25	Vpp
Input common mode voltage			1.9	±0.1	٧
Input resistance	Differential at DC		1		kΩ
Input capacitance	Each input to GND		2		pF
VCM common mode voltage output			1.9		٧
Analog input bandwidth (3dB)			1200		MHz
DYNAMIC ACCURACY					
Offset Error	Auto Correction Disabled	-20	-7.5	20	mV
Oliset Elloi	Auto Correction Enabled	-1	0	1	mV
Offset temperature coefficient			-611		μV/°C
Gain error		-5		5	%FS
Gain temperature coefficient			0.005		%FS/°C
Differential nonlinearity	f <sub>IN</sub> = 230 MHz	-1	±0.9	2	LSB
Integral nonlinearity	f <sub>IN</sub> = 230 MHz	-5	±1.5	5	LSB
CLOCK INPUT					
Input clock frequency		40		500	MHz
Input clock amplitude			2		Vpp
Input clock duty cycle		40%	50%	60%	
Internal clock biasing			0.9		V

Product Folder Links: ADS54T04



#### **ELECTRICAL CHARACTERISTICS**

Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{\text{MIN}} = -40^{\circ}\text{C}$  to  $T_{\text{MAX}} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	MIN TYP	MAX	UNITS	
Auto Co				Enabled	Disabled		Vpp	
DYNAMI	C AC CHARACTERISTICS <sup>(1)</sup> –	Burst Mode Enabled: 12bit High	n Resolution	Output Data				
		f <sub>IN</sub> = 10 MHz		60.8	60.8			
		f <sub>IN</sub> = 100 MHz		60.7	60.8			
SNR	Signal to Noise Ratio	f <sub>IN</sub> = 230 MHz	59	60.6	60.7		dBFS	
		f <sub>IN</sub> = 450 MHz		60.2	60.6			
		f <sub>IN</sub> = 700 MHz		59.4	60.1			
		f <sub>IN</sub> = 10 MHz		84	86			
		f <sub>IN</sub> = 100 MHz		84	82			
HD2,3	Second and third harmonic distortion	f <sub>IN</sub> = 230 MHz	70	80	83		dBc	
	diotortion	f <sub>IN</sub> = 450 MHz		82	84			
		f <sub>IN</sub> = 700 MHz		76	74			
		f <sub>IN</sub> = 10 MHz		77	78			
	Spur Free Dynamic Range	f <sub>IN</sub> = 100 MHz		77	78			
Non HD2,3	(excluding second and third harmonic distortion)	f <sub>IN</sub> = 230 MHz	70	77	77		dBc	
1102,0		f <sub>IN</sub> = 450 MHz		74	75			
		f <sub>IN</sub> = 700 MHz		70	71			
	Fs/2-Fin interleaving spur	f <sub>IN</sub> = 10 MHz		92	80			
		f <sub>IN</sub> = 100 MHz		83	79			
IL		f <sub>IN</sub> = 230 MHz	70	83	79		dBc	
		f <sub>IN</sub> = 450 MHz		79	76			
		f <sub>IN</sub> = 700 MHz		75	73			
		f <sub>IN</sub> = 10 MHz		60.6	60.7			
		f <sub>IN</sub> = 100 MHz		60.6	60.7			
SINAD	Signal to noise and distortion ratio	f <sub>IN</sub> = 230 MHz	57.5	60.5	60.7		dBc	
	ratio	f <sub>IN</sub> = 450 MHz		60.1	60.5			
		f <sub>IN</sub> = 700 MHz		59.3	60			
		f <sub>IN</sub> = 10 MHz		76.3	79.0			
		f <sub>IN</sub> = 100 MHz		76.5	77.6			
THD	Total Harmonic Distortion	f <sub>IN</sub> = 230 MHz	68	77.4	78.1		dBc	
		f <sub>IN</sub> = 450 MHz		76.3	77.9			
		f <sub>IN</sub> = 700 MHz		73.4	72.9			
IMDa	later modulation distortion	F <sub>in</sub> = 129.5 and 130.5MHz, - 7dBFS		82	82		dBFS	
IMD3	Inter modulation distortion	F <sub>in</sub> = 349.5 and 350.5MHz, - 7dBFS		80	80			
	Crosstalk			90	90		dB	
ENOB	Effective number of bits	f <sub>IN</sub> = 230 MHz		9.8	9.8		LSB	

<sup>(1)</sup> SFDR and SNR calculations do not include the DC or Fs/2 bins when Auto Correction is disabled.



#### **ELECTRICAL CHARACTERISTICS**

Typical values at  $T_A = 25^{\circ}\text{C}$ , full temperature range is  $T_{\text{MIN}} = -40^{\circ}\text{C}$  to  $T_{\text{MAX}} = 85^{\circ}\text{C}$ , ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OVER	-DRIVE RECOVERY ERROF	8				
	Input overload recovery	Recovery to within 5% (of final value) for 6dB overload with sine wave input		2		ns
SAMP	LE TIMING CHARACTERIS	TICS				
rms	Aperture Jitter	Sample uncertainty		100		fs rms
		ADC sample to digital output, auto correction disabled		38		Clock
		ADC sample to digital output, auto correction enabled		50		Cycles
	Data Latency	ADC sample to digital output, Decimation filter enabled, Auto correction disabled		74		Sampling clock Cycles
	Over-range Latency	ADC sample to over-range output		12		Clock Cycles

#### **ELECTRICAL CHARACTERISTICS**

The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
DIGITA	L INPUTS – SRESET, SCLK, SDE	NB, SDIO, ENABLE			'	
	High-level input voltage	All digital inputs support 1.8V and 3.3V logic	0.7 x IOVDD			V
	Low-level input voltage	levels.			0.3 x IOVDD	V
	High-level input current		-50		200	μΑ
	Low-level input current		-50		50	μΑ
	Input capacitance			5		pF
DIGITA	L OUTPUTS – SDO					
	High-level output voltage	Iload = -100uA	IOVDD – 0.2			V
	nigh-level output voltage	Iload = -2mA	0.8 x IOVDD			V
		Iload = 100uA			0.2	
	Low-level output voltage	Iload = 2mA			0.22 x IOVDD	V
DIGITA	L INPUTS – SYNCP/N, TRIGGERF	P/N				
$V_{\text{ID}}$	Differential input voltage		250	350	450	mV
$V_{\text{CM}}$	Input common mode voltage		1.125	1.2	1.375	V
$t_{SU}$			500			ps
DIGITA	L OUTPUTS – DA[11:0]P/N, DACI	.KP/N, OVRAP/N, SYNCOUTP/N, TRDYP/N, HF	RESP/N, DB[11:0	)]P/N, DBC	LKP/N, O	/RBP/N,
$V_{OD}$	Output differential voltage	lout = 3.5mA	250	350	450	mV
$V_{\text{OCM}}$	Output common mode voltage	lout = 3.5mA	1.125	1.25	1.375	V
t <sub>suA</sub>		$F_s$ = 500Msps, Data valid to zero-crossing of DACLK	600	800		ps
t <sub>hA</sub>		F <sub>s</sub> = 500Msps, Zero-crossing of DACLK to data becoming invalid	600	790		ps
t <sub>suB</sub>		$F_s = 500 Msps$ , Data valid to zero-crossing of DBCLK	700	900		ps
t <sub>hB</sub>		F <sub>s</sub> = 500Msps, Zero-crossing of DBCLK to data becoming invalid	500	600		ps



The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
t <sub>PD</sub>	F <sub>s</sub> = 500Msps, CLKIN falling edge to DACLK, DBCLK rising edge	3.28	3.48	3.74	ns
t <sub>RISE</sub>	10% - 90%	100	150	200	ps
t <sub>FALL</sub>	90% - 10%	100	150	200	ps

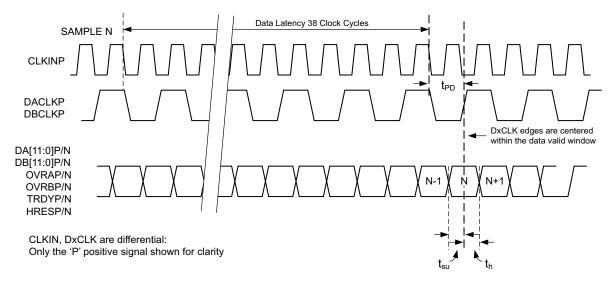
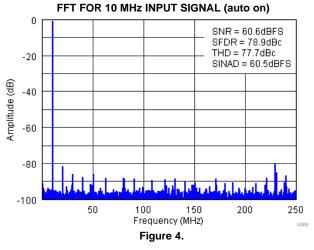


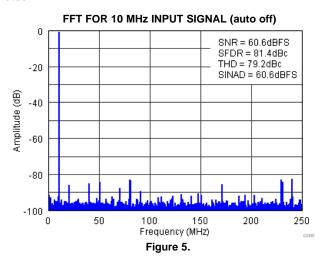
Figure 3. Timing Diagram for 12-bit DDR Output

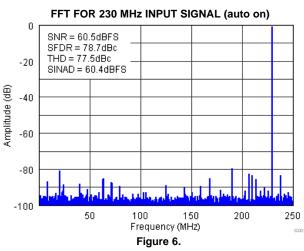


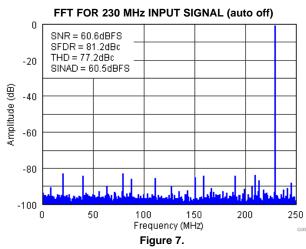
#### TYPICAL CHARACTERISTICS

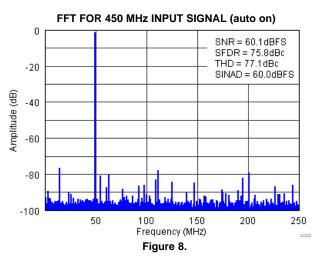
Typical values at TA =  $+25^{\circ}$ C, full temperature range is T<sub>MIN</sub> =  $-40^{\circ}$ C to T<sub>MAX</sub> =  $+85^{\circ}$ C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

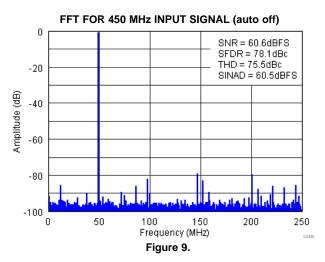












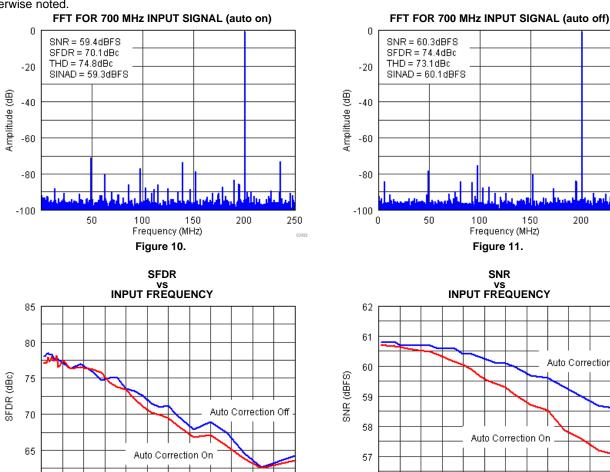


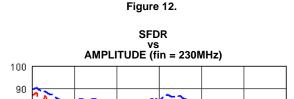
200

250

## TYPICAL CHARACTERISTICS (continued)

Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.





750

Input Frequency (MHz)

1000

1250

1500

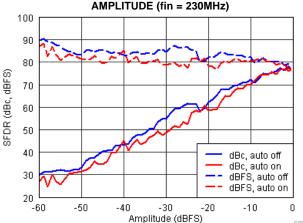
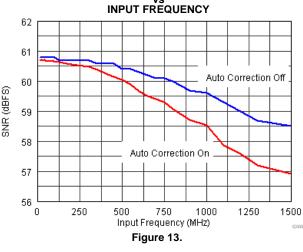
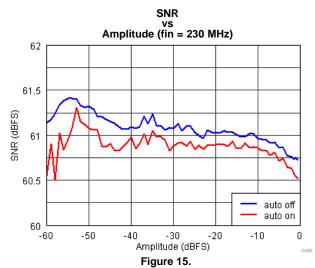


Figure 14.





Copyright © 2012-2014, Texas Instruments Incorporated

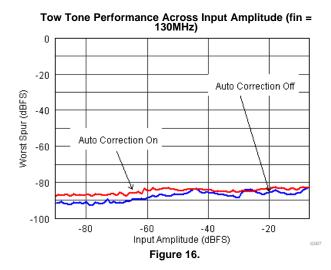
60

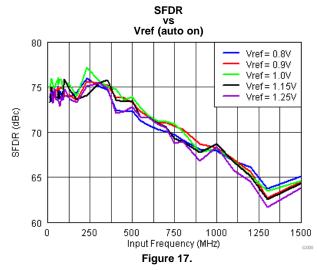
0

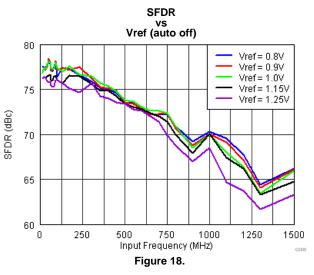
250

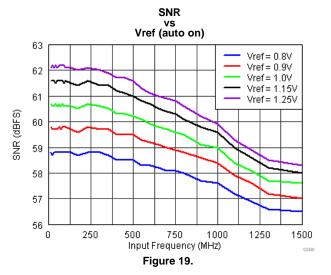


Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.











Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

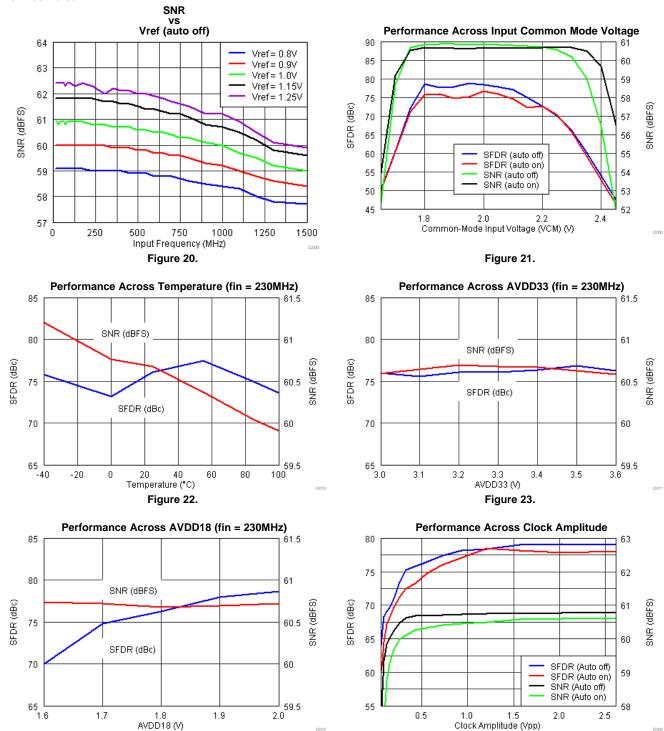
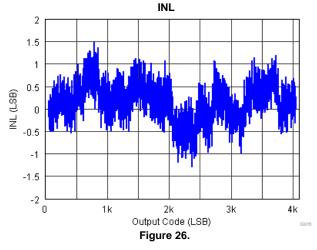


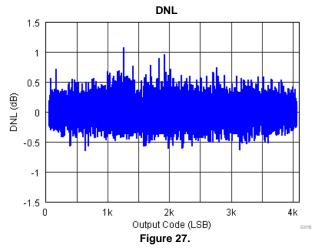
Figure 24.

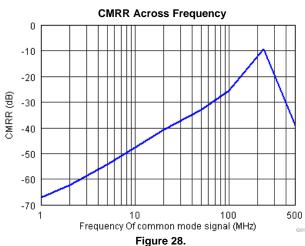
Figure 25.

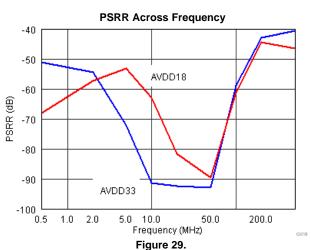


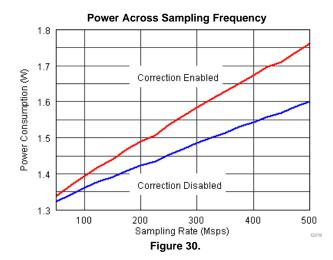
Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.













Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

#### SFDR Across Input and Sampling Frequencies (auto on)

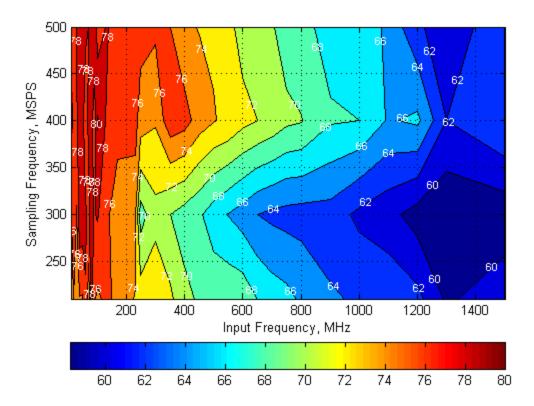


Figure 31.



Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

#### SFDR Across Input and Sampling Frequencies (auto off)

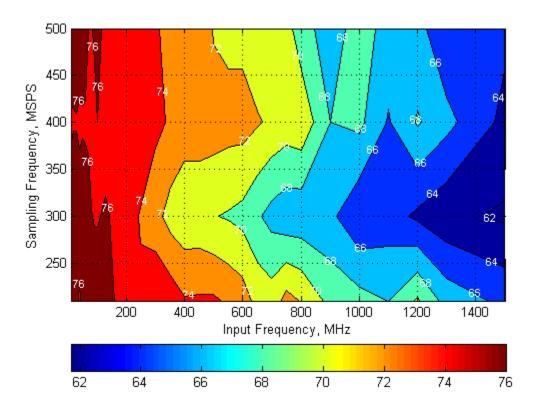


Figure 32.



Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

#### SNR Across Input and Sampling Frequencies (auto on)

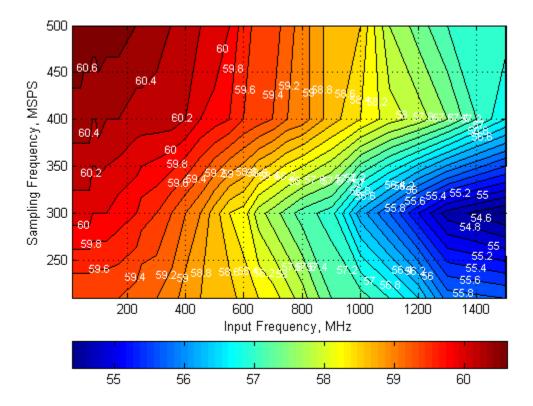


Figure 33.



Typical values at TA = +25°C, full temperature range is  $T_{MIN}$  = -40°C to  $T_{MAX}$  = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

#### SNR Across Input and Sampling Frequencies (auto on)

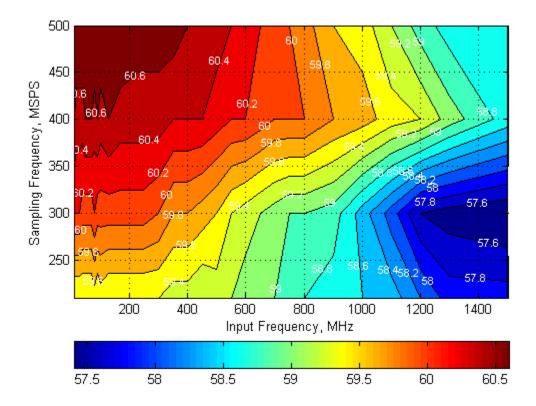


Figure 34.

Copyright © 2012–2014, Texas Instruments Incorporated



#### **FEATURES**

#### **POWER DOWN MODES**

The ADS54T04 can be configured via SPI write (address x37) to a stand-by, light or deep sleep power mode which is controlled by the ENABLE pin. The sleep modes are active when the ENABLE pin goes low. Different internal functions stay powered up which results in different power consumption and wake up time between the two sleep modes.

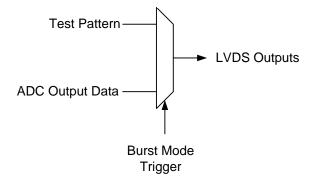
Sleep mode	Wake up time	Power Consumption Auto correction disabled	Power Consumption Auto correction enabled
Complete Shut Down	2.5 ms	7mW	7mW
Stand-by	100µs	7mW	7mW
Deep Sleep	20µs	282mW	370mW
Light Sleep	2µs	549mW	650mW

#### **TEST PATTERN OUTPUT**

The ADS54T04 can be configured to output different test patterns that can be used to verify the digital interface is connected and working properly. To enable the test pattern mode, the high performance mode 1 has to be disabled first via SPI register write. Then different test patterns can be selected by configuring registers x3C, x3D and x3E. All three registers must be configured for the test pattern to work properly.

First set HP1 = 0 (Addr 0x01, D01)

Internally the test pattern replaces the sampled data from the ADC. However at the LVDS outputs the output data is still subject to burst mode operation. In low resolution output the LSBs of the test pattern are replaced with 0s.



Register Address	All 0s	All 1s	Toggle (0xAAA => 0x555)	Toggle (0xFFF => 0x000)
0x3C	0x8000	0xBFFC	0x9554	0xBFFC
0x3D	0x0000	0x3FFC	0x2AA8	0x0000
0x3E	0x0000	0x3FFC	0x1554	0x3FFC

Register Address		Custom Pattern														
	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
x3C	1	0													0	0
x3D	0	0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	0	0
x3E	0	0													0	0

For normal operation, set HP1 = 1 (Addr 0x01, D01) and 0x3C, 0x3D, 0x3E all to 0.



#### **CLOCK INPUT**

The ADS54T04 clock input can be driven differentially with a sine wave, LVPECL or LVDS source with little or no difference in performance. The common mode voltage of the clock input is set to 0.9V using internal  $2k\Omega$  resistors. This allows for AC coupling of the clock inputs. The termination resistors should be placed as close as possible to the clock inputs in order to minimize signal reflections and jitter degradation.

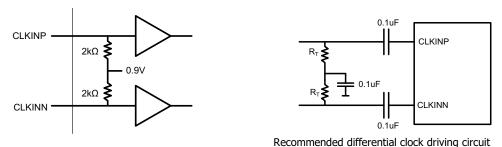


Figure 35. Recommended Differential Clock Driving Circuit

#### **SNR AND CLOCK JITTER**

The signal to noise ratio of the ADC is limited by three different factors: the quantization noise is typically not noticeable in pipeline converters and is 72dB for a 12bit ADC. The thermal noise limits the SNR at low input frequencies while the clock jitter sets the SNR for higher input frequencies.

$$SNR_{ADC}[dBc] = -20 \times log \sqrt{10 - \frac{SNR_{Quantization\_Noise}}{20}}^2 + \left(10 - \frac{SNR_{ThermalNoise}}{20}\right)^2 + \left(10 - \frac{SNR_{Jitter}}{20}\right)^2}$$
(1)

The SNR limitation due to sample clock jitter can be calculated as following:

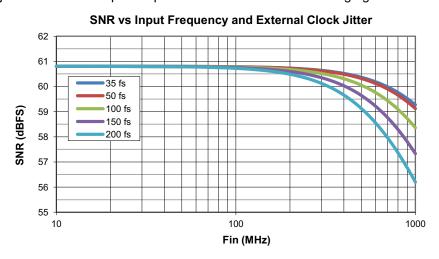
$$SNR_{Jitter} [dBc] = -20 \times log(2\pi \times f_{IN} \times t_{Jitter})$$
(2)

The total clock jitter (TJitter) has three components – the internal aperture jitter (100fs for ADS54T04) which is set by the noise of the clock input buffer, the external clock jitter and the jitter from the analog input signal. It can be calculated as following:

$$T_{\text{Jitter}} = \sqrt{\left(T_{\text{Jitter,Ext.Clock\_Input}}\right)^2 + \left(T_{\text{Aperture\_ADC}}\right)^2}$$
(3)

External clock jitter can be minimized by using high quality clock sources and jitter cleaners as well as bandpass filters at the clock input while a faster clock slew rate improves the ADC aperture jitter.

The ADS54T04 has a thermal noise of 60.8 dBFS and internal aperture jitter of 100fs. The SNR depending on amount of external jitter for different input frequencies is shown in the following figure.



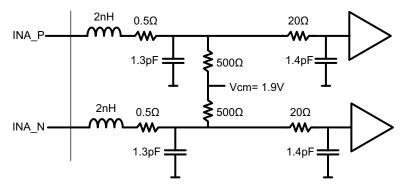
Product Folder Links: ADS54T04



#### ANALOG INPUTS

The ADS54T04 analog signal inputs are designed to be driven differentially. The analog input pins have internal analog buffers that drive the sampling circuit. As a result of the analog buffer, the input pins present a high impedance input across a very wide frequency range to the external driving source which enables great flexibility in the external analog filter design as well as excellent  $50\Omega$  matching for RF applications. The buffer also helps to isolate the external driving circuit from the internal switching currents of the sampling circuit which results in a more constant SFDR performance across input frequencies.

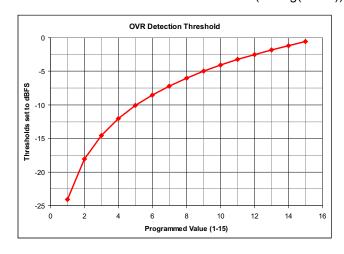
The common-mode voltage of the signal inputs is internally biased to 1.9V using  $500\Omega$  resistors which allows for AC coupling of the input drive network. Each input pin (INP, INM) must swing symmetrically between (VCM + 0.25V) and (VCM - 0.25V), resulting in a 1.0Vpp (default) differential input swing. The input sampling circuit has a 3dB bandwidth that extends up to 1.2GHz.



#### **OVER-RANGE INDICATION**

The ADS54T04 provides a fast over-range indication on the OVRA/B pins. The fast OVR is triggered if the input voltage exceeds the programmable overrange threshold and it gets presented after just 12 clock cycles enabling a quicker reaction to an overrange event. The OVR threshold can be configured using SPI register writes.

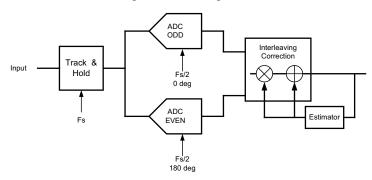
The input voltage level at which the overload is detected is referred to as the threshold and is programmable using the Over-range threshold bits. The threshold at which fast OVR is triggered is (full-scale × [the decimal value of the FAST OVR THRESH bits] /16). After reset, the default value of the over-range threshold is set to 15 (decimal) which corresponds to a threshold of 0.56dB below full scale (20\*log(15/16)).





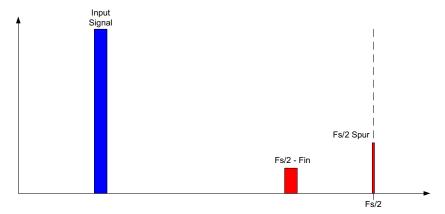
#### INTERLEAVING CORRECTION

Each of the two data converter channels consists of two interleaved ADCs each operating at half of the ADC sampling rate but 180° out of phase from each other. The front end track and hold circuitry is operating at the full ADC sampling rate which minimizes the timing mismatch between the two interleaved ADCs. In addition the ADS54T04 is equipped with internal interleaving correction logic that can be enabled via SPI register write.



The interleaving operation creates 2 distinct and interleaving products:

- Fs/2 Fin: this spur is created by gain timing mismatch between the ADCs. Since internally the front end track and hold is operated at the full sampling rate, this component is greatly improved and mostly dependent on gain mismatch.
- · Fs/2 Spur: due to offset mismatch between ADCs



The auto correction loop can be enabled via SPI register write in address 0x01. By default it is disabled for lowest possible power consumption. The DC correction function can be enabled in 0x03 & 0x1A for chA and chB respectively. The default settings for the auto correction function should work for most applications. However please contact Texas Instruments if further fine tuning of the algorithm is required.

The auto correction function yields best performance for input frequencies below 250MHz.



#### **RECEIVE MODE: DECIMATION FILTER**

Each channel has a digital filter in the data path as shown in Figure 36. The filter can be programmed as a low-pass or a high-pass filter and the normalized frequency response of both filters is shown in Figure 37.

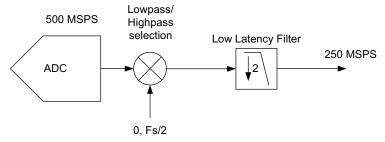


Figure 36.

The decimation filter response has a 0.1dB pass band ripple with approximately 41% pass-band bandwidth. The stop-band attenuation is approximately 40dB.

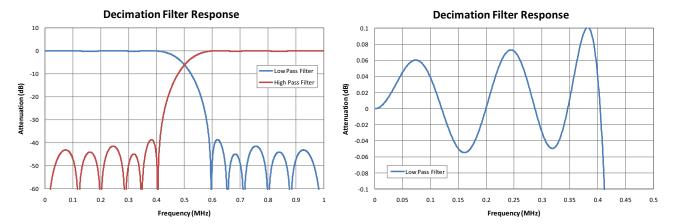


Figure 37.

Copyright © 2012–2014, I

Product Folder Links: ADS54T04

24



#### FEEDBACK MODE: BURST MODE

In burst mode the output data is alternated between a high resolution 12bit output of 2N samples and a low resolution 9 or 11bit output of  $2^{N+3}$  samples. Burst mode is enabled through SPI register write and there are two basic operating modes available – a manual trigger mode where the high resolution output is initiated through external trigger and an auto trigger mode where the internal logic transitions to high resolution output immediately after transmitting the last low resolution sample. Upon enabling burst mode through a SPI register write, the ADS54T04 transmits  $2^{13}$  low resolution samples and the trigger command is locked out until completion.

The parameter N can be changed via SPI at any time. It will go in effect with the next output cycle starting with transmission of low resolution samples. The default value for N after reset is N=10.

N limit	10 (minimum)	25 (maximum)
Number of low resolution samples per cycle (2 <sup>N+3</sup> )	8,192	268,435,456
Number of high resolution samples per cycle (2N)	1,024	33,554,432
Total amount of samples per cycle	9,216	301,989,888
Maximum number of high resolution (12-bit) samples per 1 second	55.6M	55.6M

#### **Manual Trigger Mode**

The control of the high resolution output is shown below along with the two output flags (TRDY and HRES).

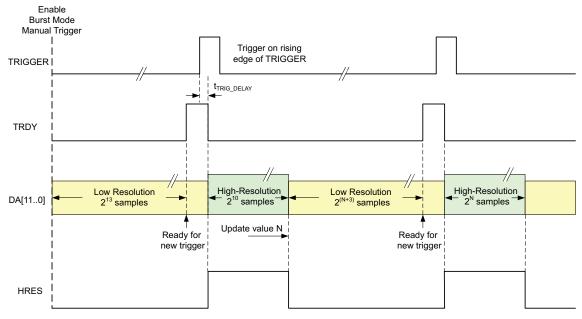


Figure 38. Triggering High Resolution Mode and Lockout Time

After enabling burst mode, the output data DA[11..0] and DB[11..0] are forced to low resolution mode for 2<sup>13</sup> samples. During that period any trigger signal is ignored. The completion of the low resolution sample cycle is signaled by a logic high on the TRDY output pins indicating that a high resolution (12-bit) data output burst can be triggered by a low to high transition on the TRIGGER input. The ADC monitors the TRIGGER input at each rising edge of the input clock.

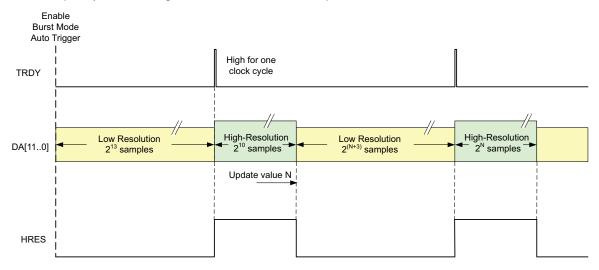
The high resolution output data starts with a delay of  $t_{TRIG\_DELAY} = 1-2$  DA/BCLK clock cycles and is indicated through the HRES data flag which stays high for all  $2^N$  high resolution samples. At completion the register value for N is verified and transmission of  $2^{(N+3)}$  low resolution data immediately follows. Once the last low resolution sample is output on the output data bus, the flag TRDY is asserted high again indicating the end of the lockout period and the next  $2^N$  high resolution samples can be triggered again.



#### **Auto Trigger Mode**

This mode is enabled by setting the auto trigger bit via SPI register write and the DA/DB data outputs start in low resolution for 2<sup>13</sup> samples. Immediately following completion of transmission of the last low resolution sample, the outputs automatically start transmitting 2<sup>10</sup> high resolution samples without the need for external trigger ensuring maximum efficiency. Any input signal on the TRIGGER pins is ignored and the TRDY flag will go high only for one clock cycle with the start of the high resolution data.

The output flag HRES is aligned with the 2<sup>N</sup> high resolution output samples and the parameter N can be changed until the next output cycle starts again with low resolution output data.



#### **High Resolution Output Data**

After trigger, the data outputs DA[11..0]/DB[11..0] are 12-bit resolution for  $2^N$  samples, where N is a programmable register with a range 10  $\leq$ N $\leq$ 25 (corresponding to 1024 to 33554432 samples).

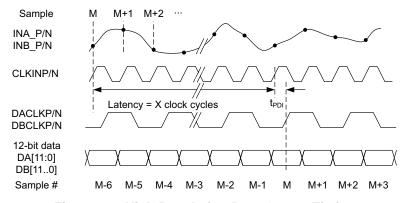


Figure 39. High Resolution Data Output Timing

After the high resolution data, the data output returns to low resolution mode, the logic level of the HRES flag returns low and the trigger is locked out for  $2^{(N+3)}$  samples. N is the sample integer resulting in a maximum output duty cycle of 1/9. During the trigger lockout time, a low to high transition on TRIGGERP/N will be ignored. After the  $2^{N+3}$  low resolution samples, the TRIGGERP/N is re-enabled for the next valid data burst.

# **Low Resolution Output Data**

There are two different options for the low resolution output data and the selection is made through SPI register control. The data can either be output at full speed (ADC sampling rate) with the output resolution limited to 9bit (9 MSBs). Alternatively the output resolution can be selected to 11bit (11 MSBs) but at a reduced effective data rate where every 4th sample gets repeated four times.



#### Full Speed - 9bit

The output data rate and timing is exactly the same as the high resolution data – only the output resolution is limited to the 9 MSBs.

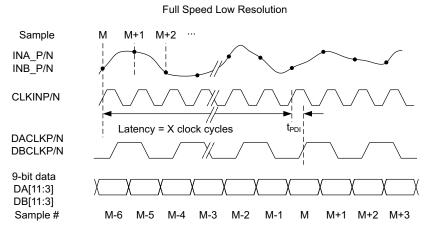


Figure 40. Full Rate Low Resolution Output Data Timing

#### **Decimated Low Resolution Output Data**

In decimated low resolution mode the output data is limited to 11-bits and every sample is repeated four times so the effective data rate is 1/4 of ADC sampling rate. The latency of the ADC sample to output sample is exactly the same as for high resolution data – there is no uncertainty in which conversion sample results in the valid output data. This is because the output continues to run at the ADC sample rate – only the resolution is changed and three out of four samples are deleted.

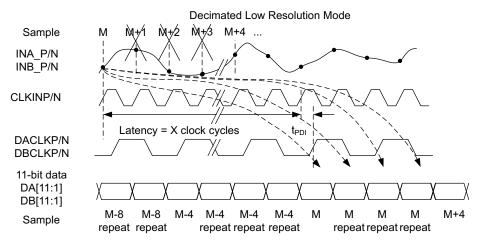
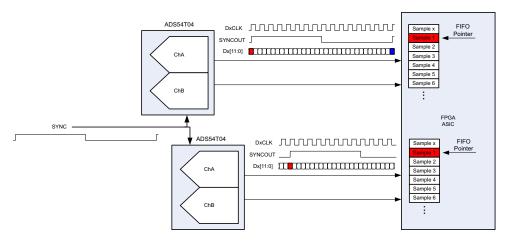


Figure 41. Decimated Low Resolution Output Data Timing Diagram



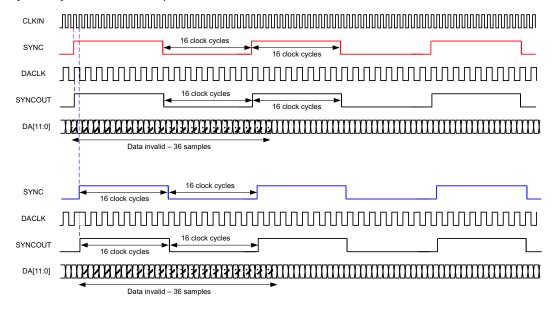
#### MULTI DEVICE SYNCHRONIZATION

The ADS54T04 simplifies the synchronization of data from multiple ADCs in one common receiver. Upon receiving the initial SYNC input signal, the ADS54T04 resets all the internal clocks and digital logic while also starting a SYNCOUT signal which operates on a 5bit counter (32 clock cycles). Therefore by providing a common SYNC signal to multiple ADCs their output data can be synchronized as the SYNCOUT signal marks a specific sample with the same latency in all ADCs. The SYNCOUT signal then can be used in the receiving device to synchronize the FIFO pointers across the different input data streams. Thus the output data of multiple ADCs can be aligned properly even if there are different trace lengths between the different ADCs.



The SYNC input signal should be a one time pulse to trigger the periodic 5-bit counter for SYNCOUT or a periodic signal repeating every 32 CLKIN clock cycles. It gets registered on the rising edge of the ADC input clock (CLKIN). Upon registering the initial rising edge of the SYNC signal, the internal clocks and logic get reset which results in invalid output data for 36 samples (1 complete sync cycle and 4 additional samples). The SYNCOUT signal starts with the next output clock (DACLK) rising edge and operates on a 5-bit counter. If a SYNCIN rising edge gets registered at a new position, the counter gets reset and SYNCOUT starts from the new position.

Since the ADS54T04 output interface operates with a DDR clock, the synchronization can happen on the rising edge or falling edge sample. Synchronization on the falling edge sample will result in a half cycle clock stretch of DA/BCLK. For convenience the SYNCOUT signal is available on the ChA/B output LVDS bus. When using decimation the SYNCOUT signal still operates on 32 clock cycles of CLKIN but since the output data is decimated by 2, only the first 18 samples should be discarded.



Submit Documentation Feedback

Copyright © 2012–2014, Texas Instruments Incorporated



#### PROGRAMMING INTERFACE

The serial interface (SIF) included in the ADS54T04 is a simple 3 or 4 pin interface. In normal mode, 3 pins are used to communicate with the device. There is an enable (SDENB), a clock (SCLK) and a bi-directional IO port (SDIO). If the user would like to use the 4 pin interface one write must be implemented in the 3 pin mode to enable 4 pin communications. In this mode, the SDO pin becomes the dedicated output. The serial interface has an 8-bit address word and a 16-bit data word. The first rising edge of SCLK after SDENB goes low will latch the read/write bit. If a high is registered then a read is requested, if it is low then a write is requested. SDENB must be brought high again before another transfer can be requested. The signal diagram is shown below:

#### **Device Initialization**

After power up, it is recommended to initialize the device through a hardware reset by applying a logic low pulse on the SRESETb pin (of width greater than 20ns), as shown in Figure 42. This resets all internal digital blocks (including SPI registers) to their default condition.

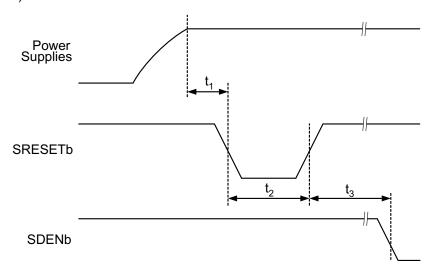


Figure 42. Device Initialization Timing Diagram

**Table 1. Reset Timing** 

	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>1</sub>	Power-on delay	Delay from power up to active low RESET pulse	3			ms
t <sub>2</sub>	Reset pulse width	Active low RESET pulse width	20			ns
t <sub>3</sub>	Register write delay	Delay from RESET disable to SDENb active	100			ns

#### Recommended Device Initialization Sequence:

- 1. Power up
- 2. Reset ADS54T04 using hardware reset.
- 3. Apply clock and input signal.
- 4. Set register 0x01 bit D15 to "1" (ChA Corr EN) and bit D9 to "1" (ChB Corr EN) to enable gain/offset correction circuit and other desired registers.
- 5. Set register 0x03 and 0x1A bit D14 to "1" (Start Auto Corr ChA/B). This clears and resets the accumulator values in the DC and gain correction loop.
- 6. Set register 0x03 and 0x1A bit D14 to "0" (Start Auto Corr ChA/B). This starts the DC and gain auto-correction loop.

Product Folder Links: ADS54T04



#### **Serial Register Write**

The internal register of the ADS54T04 can be programmed following these steps:

- 1. Drive SDENB pin low
- 2. Set the R/W bit to '0' (bit A7 of the 8 bit address)
- 3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be written
- 4. Write 16bit data which is latched on the rising edge of SCLK

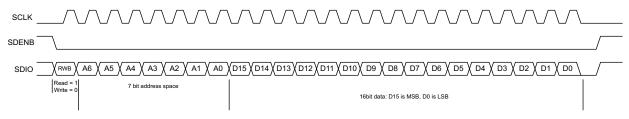


Figure 43. Serial Register Write Timing Diagram

	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
f <sub>SCLK</sub>	SCLK frequency (equal to 1/tSCLK)	>DC		20	MHz
t <sub>SLOADS</sub>	SDENB to SCLK setup time	25			ns
t <sub>SLOADH</sub>	SCLK to SDENB hold time	25			ns
t <sub>DSU</sub>	SDIO setup time	25			ns
t <sub>DH</sub>	SDIO hold time	25			ns

<sup>(1)</sup> Typical values at +25°C; minimum and maximum values across the full temperature range: TMIN = -40°C to TMAX = +85°C, AVDD3V = 3.3V, AVDD, DRVDD = 1.9V, unless otherwise noted.

#### **Serial Register Readout**

The device includes a mode where the contents of the internal registers can be read back using the SDO/SDIO pins. This read-back mode may be useful as a diagnostic check to verify the serial interface communication between the external controller and the ADC.

- 1. Drive SDENB pin low
- 2. Set the RW bit (A7) to '1'. This setting disables any further writes to the registers
- 3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be read.
- 4. The device outputs the contents (D15 to D0) of the selected register on the SDO/SDIO pin
- 5. The external controller can latch the contents at the SCLK rising edge.
- 6. To enable register writes, reset the RW register bit to '0'.

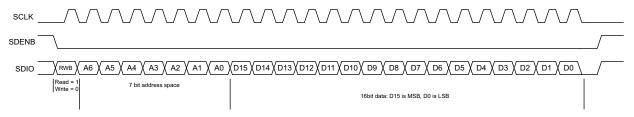


Figure 44. Serial Register Read Timing Diagram



# SERIAL REGISTER MAP(2)

(2) Multiple functions in a register can be programmed in a single write operation.

Register Address								Regist	er Data							
A7-A0 IN HEX	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	DecFil/ Burst	0	ChA High/ Low Pass	0	0	ChB High/ Low Pass	0	0	0	Burst rate	0	0	Auto Trigger	0	0
1	ChA Corr EN	0	0	0	0	0	ChB Corr EN	0	0	0	0	0	Data Format	0	Hp Mode1	0
2	0	0 1 0 0 0 Over-range threshold 0 0 0 0 0									0	0				
3	0	DC Offset Corr ChA	0	0	1	0	1	1	0	0	0	1	1	0	0	0
Е		Sync Select											0	0		
F		Sync	Select		0	0	0	0	0		VREF Set	İ	0	0	0	0
1A	0	DC Offset Corr ChB	0	0	1	0	1	1	0	0	0	1	1	0	0	0
2B	0	0	0	0	0	0	0				1	Temp Senso	or			
2C				I.			<u>'</u>	Re	set							
34	0	0		Burst M	Mode N		0	0	0	0	0	0	0	0	0	0
37			Sleep	Modes			0	0	0	0	0	0	0	0	0	0
38					HP Mode2	2				BIAS EN	SYNC EN	TRIGEN	1	1	1	1
ЗА							al LVDS ination	0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN
66							L	VDS Outp	ut Bus A E	N						
67	LVDS Output Bus B EN															

#### **DESCRIPTION OF SERIAL INTERFACE REGISTERS**

Register Address		Register Data														
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	Dec Fil/ Burst	0	ChA High/ Low Pass	0	0	ChB High/ Low Pass	0	0	0	Burst rate	0	0	Auto Trigger	0	0

D15 **3/4 Wire SPI** Enables 4-bit serial interface when set

Default 0

- 0 3 wire SPI is used with SDIO pin operating as bi-directional I/O port
- 4 wire SPI is used with SDIO pin operating as data input and SDO pin as data output port.

D14 **DecFil/ Burst** 2x decimation filter (Receive Mode) is enabled when bit is set

Default 0

- 0 Burst mode enable
- 1 2x decimation filter enabled

D12 ChA High/Low (Decimation filter must be enabled first: set bit D14)

**Pass** 

Default 0

- 0 Low Pass
- 1 High Pass



D9	ChB High/Low Pass Default 0	(Decimation filter must be enabled first: set bit D14)
0	Low Pass	
1	High Pass	
D5	Burst Rate Default 0	Low resolution output data rate in burst mode
0	Low resolution (9	bit) full output rate
1	Decimated low re	solution output (4x decimation, 11bit resolution)
D2	Auto Trigger Default 0	Enables auto trigger mode in burst mode without the need to control the trigger pin.
0	Manual trigger me	ode using the external trigger input pin
1	Auto trigger mode	e enabled

Register Address		Register Data														
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1	ChA Corr EN	0	0	0	0	0	ChB Corr EN	0	0	0	0	0	Data Format	0	HP Mode1	0

Address																
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1	ChA Corr EN	0	0	0	0	0	ChB Corr EN	0	0	0	0	0	Data Format	0	HP Mode1	0
D15 <b>ChA</b>	Corr	FN (s	hould	he er	nabled	l for n	naxim	um ne	rform	ance)						

Default 0

- auto gain correction disabled 0
- auto gain correction enabled

#### D9 ChB Corr EN (should be enabled for maximum performance)

Default 0

- auto gain correction disabled 0
- 1 auto gain correction enabled

#### D3 **Data Format**

Default 0

- 0 Two's complement
- 1 Offset Binary

#### **HP Mode 1** D1

Default 0

1 Must be set to 1 for optimum performance



www.ti.com

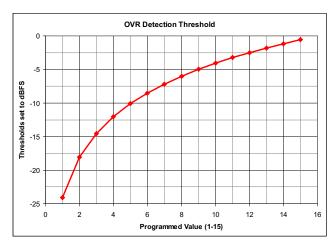
Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2	0	1	0	0	0	Over-range threshold				0	0	0	0	0	0	0

#### D14 Read back 1.

#### D10-D7 Over-range threshold

The over-range detection is triggered 12 output clock cycles after the overload condition occurs. The threshold at which the OVR is triggered =  $1.0V \times [\text{decimal value of } < \text{Over-range threshold} >]/16$ . After power up or reset, the default value is 15 (decimal) which corresponds to a OVR threshold of 0.56dB below fullscale ( $20*\log(15/16)$ ). This OVR threshold is applicable to both channels.

Default 1111



Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3	0	DC Offset Coff ChA	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14 DC Offset Corr ChA Starts DC offset correction loop for ChA

Default 1

0 Starts offset correction loop for ChA 1 DC offset correction loop is cleared

D11, 9, 8, 4, 3 Must be set to 1 for maximum performance

Default 1

Copyright © 2012–2014, Texas Instruments Incorporated

#### SLAS917B - DECEMBER 2012-REVISED JANUARY 2014



www.ti.com

Register **Register Data** Address D15 D14 D13 D12 D11 D7 D4 D3 D1 D0 A7-A0 in D10 D9 D8 D6 D5 D2 hex 0 Ε Sync Select 0

D15-D2 Sync Select Sync selection for the clock generator block (also

Default 1010 1010

1010 10

Sync selection for the clock generator block (also

need to see address 0x0F)

0000 0000 0000 00 Sync is disabled

0101 0101 0101 01 Sync is set to one shot (one time synchronization only)

1010 1010 1010 10 Sync is derived from SYNC input pins

1111 1111 111 not supported

Register Address								Regist	er Data							
A7-A0 in hex	D15 D14 D13 D12				D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
F		Sync Select				0	0	0	0	\	/REF Se	el	0	0	0	0

D15-D12 Sync Select Sync selection for the clock generator block

Default 1010

0000 Sync is disabled

O101 Sync is set to one shot (one time synchronization only)

1010 Sync is derived from SYNC input pins

1111 not supported

D6-D4 VREF SEL Internal voltage reference selection

Default 000

000 1.0V 001 1.25V 010 0.9V 011 0.8V 100 1.15V

Others external reference

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1A	0	DC Offset Corr ChB	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14 DC Offset Corr ChB Starts DC offset correction loop for ChB

Default 1

Starts offset correction loop for ChB
 DC offset correction loop is cleared

D11, 9, 8, 4, 3 Must be set to 1 for maximum performance

Default 1

Submit Documentation Feedback



#### www.ti.com

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2B	0	0	0	0	0	0	0	Temp Sensor								

D8-D0 **Temp Sensor** Internal temperature sensor value – read only

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2C								Re	set							

D15-D0 Reset

Default 0000 This is a software reset to reset all SPI registers to their default value. Self

clears to 0.

1101001011110000 Perform software reset

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
34	0	0		Burst Mode N				0	0	0	0	0	0	0	0	0

D13-D10 Burst Mode N

Default 0000

This is the parameter that sets the amount of high resolution

samples in burst mode

0000 N = 10 0001 N = 11

1111 N = 25

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
37			Sleep	Modes			0	0	0	0	0	0	0	0	0	0

D15-D14 Sleep Modes Sleep mode selection which is controlled by the ENABLE pin. Sleep modes are active when

Default 00 ENABLE pin goes low.

000000 Complete shut down Wake up time 2.5 ms
100000 Stand-by mode Wake up time 100 μs
110000 Deep sleep mode Wake up time 20 μs
110101 Light sleep mode Wake up time 2 μs

Copyright © 2012–2014, Texas Instruments Incorporated

Product Folder Links: *ADS54T04* 



**STRUMENTS** 

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
38		HP Mode 2									SYNC	TRIG	1	1	1	1

hex         HP Mode 2         Bias SYNC TRIG 1         1         1         1	Addr	ess																
			D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
EN EN EN	38	3				Н	P Mode	2				Bias EN	SYNC EN	TRIG EN	1	1	1	1

D15-D7 **HP Mode 2** 

Default 111111111

Set to 1 for normal operation 1

D6 **BIAS EN** Enables internal fuse bias voltages - can be disabled after

power up to save power. Default 1

0 Internal bias powered

down

1 Internal bias enabled

SYNC EN D5 Enables the SYNC input buffer.

Default 1

0 SYNC input buffer

disabled

1 SYNC input bffer enabled

D4 TRIG EN Enables the TRIGGER input buffer.

Default 1

0 TRIGGER input buffer

disabled

TRIGGER input bffer

enabled

D3-D0 Read back 1

Submit Documentation Feedback

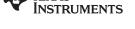
Copyright © 2012–2014, Texas Instruments Incorporated



#### www.ti.com

Register Address								Re	gister	Data						
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3A	LVDS Current Strength			LVDS	S SW		rnal DS nation	0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN

D15-D13	LVDS Current Strength Default 000	t	LVDS output current strength.
000	2 mA	100	3 mA
001	2.25 mA	101	3.25 mA
010	2.5 mA	110	3.5 mA
011	2.75 mA	111	3.75 mA
D12-D11	LVDS SW Default 01	LVDS	driver internal switch setting – correct range must be set for setting in D15-D13
01	2 mA to 2.75 r	nA	
11	3mA to 3.75m	A	
D10-D9	Internal LVDS Termination Default 00	•	Internal termination
00	2 kΩ		
01	200 Ω		
10	200 Ω		
11	100 Ω		
D4	DACLK EN Default 1		Enable DACLK output buffer
0	DACLK output	buffer	powered down
1	DACLK output	buffer	enabled
D3	DBCLK EN Default 1		Enable DBCLK output buffer
0	DBCLK output	buffer	powered down
1	DBCLK output	buffer	enabled
D1	OVRA EN Default 1	Enabl	e OVRA output buffer
0	OVRA output l	ouffer p	owered down
1	OVRA output l	ouffer e	enabled
D0	OVRB EN Default 1	Enabl	e OVRB output buffer
0	OVRB output I	ouffer p	owered down
1	OVRB output I	ouffer e	enabled



www.ti.com

Register Address																
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D8 D7 D6 D5 D4 D3 D2 D1							
66		LVDS Output Bus A EN														

D15-D0	LVDS Output Bus A EN Default FFFF	Individual LVDS output pin power down for channel A
0	Output is powered down	
1	Output is enabled	
D15	corresponds to TRDYP/N (pi	ns N7, P7)
D14	corresponds to HRESP/N (pi	ns N6, P6)
D13	SYNCOUTP/N (pins N5, P5)	
D12	Pins N4, P4 (no connect pins power savings	s) which are not used and should be powered down for
D11-D0	corresponds to DA11-DA0	

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
67	LVDS Output Bus B EN															

D15-D0	<b>LVDS Output Bus B EN</b> Individual LVDS output pin power down for channel E Default FFFF	3
0	Output is powered down	
1	Output is enabled	
D15	corresponds to TRDYP/N (pins G3, G4)	
D14	corresponds to HRESP/N (pins F3, F4)	
D13	SYNCOUTP/N (pins F1, F2)	
D12	Pins E3, E4 (no connect pins) which are not used and should be powered down for power savings	
D11-D0	corresponds to DB11-DB0	



# **REVISION HISTORY**

Cł	nanges from Revision A (August 2013) to Revision B	Page
•	Added text to TRDYP/N description	4
•	Added text to HRESP/N description	4
•	Changed package from QFN to nFBGA in THERMAL INFORMATION	5
•	Added text and figure to TEST PATTERN OUTPUT section	20
•	Deleted from last paragraph in INTERLEAVING CORRECTION section	23
•	Changed second paragraph in MULTI DEVICE SYNCHRONIZATION section	28
•	Deleted Register Initialization section and added Device Initialization section	29
•	Changed Register Address E Bits D1 and D0 to 0 in SERIAL REGISTER MAP	31
•	Changed Register Address 38 Bits D3 to D0 from 0 to 1 in SERIAL REGISTER MAP	31
•	Changed Register Address 1 Bit D14 from 1 to 0	32
•	Changed Register Address E Bit D1 and D0 to 0	34
•	Changed Register Address 38 Bits D3 to D0 from 0 to 1 and add D3 to D0 Read back 1	36
•	Changed Register Address 66 D15-D10 to D15-D0 and DA11-D0 to DA11-DA0	38
•	Changed Register Address 67 D15-D10 to D15-D0	38
Cł	nanges from Original (Decmber 2012) to Revision A	Page
•	Changed D15-10 in register 66 From: Individual LVDS output pin power down for channel B To: Individual LVDS output pin power down for channel A	38
•	Changed D15 in register 66 From: corresponds to TRDYP/N (pins G3, G4) To: corresponds to TRDYP/N (pins N7, P7)	38
•	Changed D14 in register 66 From: corresponds to HRESP/N (pins F3, F4) To: corresponds to HRESP/N (pins N6, P6)	38
•	Changed D13 in Register 66 From: SYNCOUTP/N (pins F1, F2) To: SYNCOUTP/N (pins N5, P5)	38
•	Changed D12 in Register 66 From: "Pins E3, E4" To: "Pins N4, P4"	38
•	Changed D11-D10 - corresponds to DB11-DB0 in Register 66 To: D11-D0 - corresponds to DA11-D0	
•	Changed D11-D10 - corresponds to DB11-DB0 in Register 67 To: D11-D0 - corresponds to DB11-DB0	38

www.ti.com 23-May-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
ADS54T04IZAY	Active	Production	NFBGA (ZAY)   196	IFBGA (ZAY)   196 160   JEDEC TRAY (5+1)		SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS54T04I
ADS54T04IZAY.B	Active	Production	NFBGA (ZAY)   196	160   JEDEC Yes TRAY (5+1)		SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS54T04I
ADS54T04IZAYR	ADS54T04IZAYR Active Pro		NFBGA (ZAY)   196	1000   LARGE T&R	Yes	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS54T04I
ADS54T04IZAYR.B	Active	Production	NFBGA (ZAY)   196	1000   LARGE T&R	Yes	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS54T04I

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 29-Jul-2025

#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS54T04IZAYR	NFBGA	ZAY	196	1000	330.0	24.4	12.3	12.3	2.3	16.0	24.0	Q1

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 29-Jul-2025



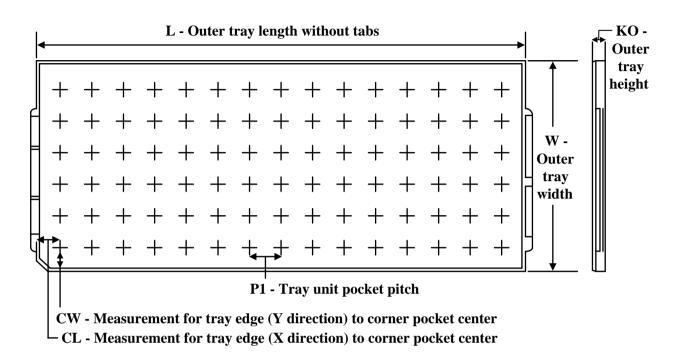
#### \*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
I	ADS54T04IZAYR	NFBGA	ZAY	196	1000	350.0	350.0	43.0



www.ti.com 29-Jul-2025

#### **TRAY**



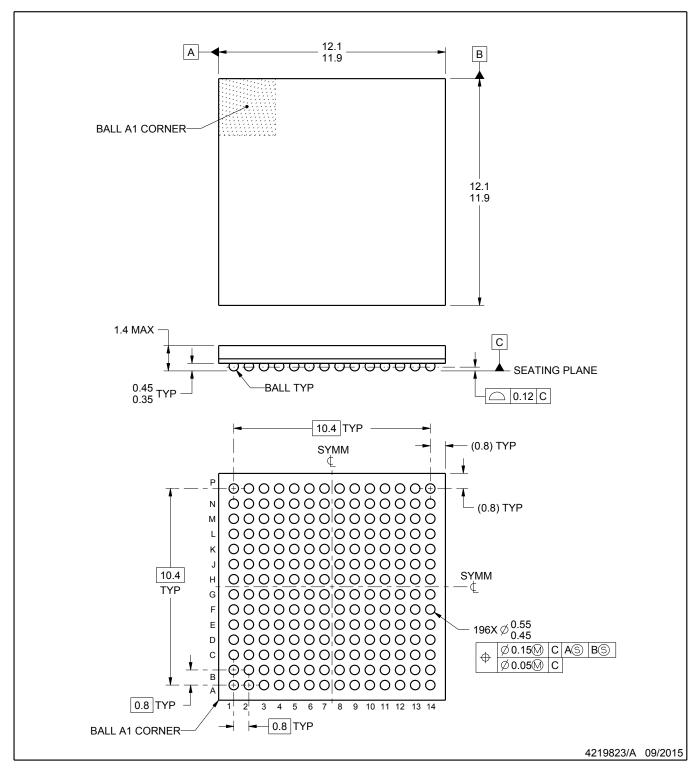
Chamfer on Tray corner indicates Pin 1 orientation of packed units.

#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	Unit array matrix	Max temperature (°C)	L (mm)	W (mm)	Κ0 (μm)	P1 (mm)	CL (mm)	CW (mm)
ADS54T04IZAY	ZAY	NFBGA	196	160	8 x 20	150	315	135.9	7620	15.4	11.2	19.65
ADS54T04IZAY.B	ZAY	NFBGA	196	160	8 x 20	150	315	135.9	7620	15.4	11.2	19.65



PLASTIC BALL GRID ARRAY

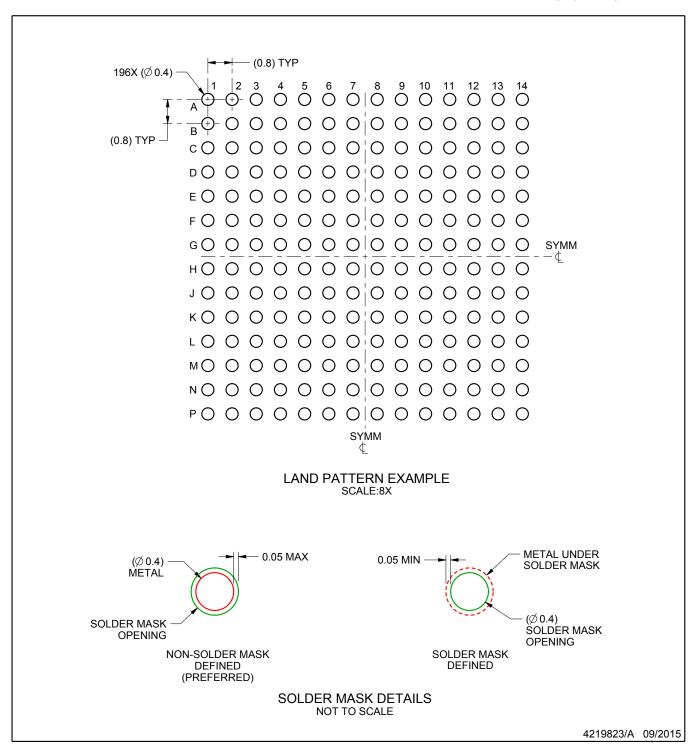


#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



PLASTIC BALL GRID ARRAY

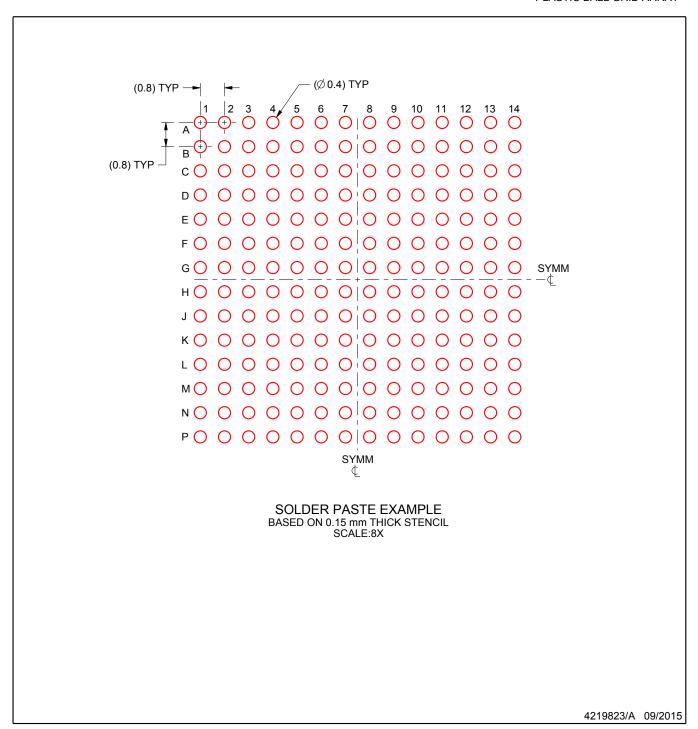


NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For information, see Texas Instruments literature number SPRAA99 (www.ti.com/lit/spraa99).



PLASTIC BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



#### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2025. Texas Instruments Incorporated